

Page : 1 of 21 Issued date : March 13, 2012 Revised date : March 15, 2012 FCC ID : BABFT0019A

RADIO TEST REPORT

Test Report No.: 32GE0069-HO-01-A-R1

Applicant : FUJITSU TEN LIMITED

Type of Equipment : Radio Detection and Ranging Device for Vehicle

Model No. : FT0019A

FCC ID : BABFT0019A

Test regulation : FCC Part 15 Subpart C: 2012

Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.

2. The results in this report apply only to the sample tested.

3. This sample tested is in compliance with the above regulation.

4. The test results in this report are traceable to the national or international standards.

5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

6. This report is a revised version of 32GE0069-HO-01-A. 32GE0069-HO-01-A is replaced with this report.

Date of test:

February 23 to March 1, 2012

Representative test engineer:

Hironobu Ohnishi Engineer of WiSE Japan, UL Verification Service

Approved by:

Masanori Nishiyama Leader of WiSE Japan, UL Verification Service



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation. *As for the range of Accreditation in NVLAP, you may refer to the WEB address,

http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 2 of 21
Issued date : March 13, 2012
Revised date : March 15, 2012
FCC ID : BABFT0019A

CONTENTS	PAGE
SECTION 1: Customer information	3
SECTION 2: Equipment under test (E.U.T.)	3
SECTION 3: Test specification, procedures & results	4
SECTION 4: Operation of E.U.T. during testing	
SECTION 5: Radiated Emission (Spurious Emission, Power Density)	9
SECTION 6: Frequency Stability	11
APPENDIX 1: Data of EMI test	
26dB and 99% Bandwidth	12
Power Density	13
Spurious Emission	14
Frequency Stability	16
APPENDIX 2: Test instruments	17
APPENDIX 3: Photographs of test setup	
Spurious Emission	
Carrier Frequency Measurement	
Frequency Stability	21

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 3 of 21 Issued date : March 13, 2012 Revised date : March 15, 2012 FCC ID : BABFT0019A

SECTION 1: Customer information

Company Name : FUJITSU TEN LIMITED

Address : 2-28, Gosho-dori 1-Chome, Hyogo-ku, Kobe 652-8510, Japan

Telephone Number : +81-78-682-2159 Facsimile Number : +81-78-671-7160 Contact Person : Shotatsu Yo

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Radio Detection and Ranging Device for Vehicle

Model No. : FT0019A

Serial No. : Refer to Section 4, Clause 4.2

Receipt Date of Sample : February 21, 2012

Country of Mass-production : Japan

Condition of EUT : Engineering prototype

(Not for Sale: This sample is equivalent to mass-produced items.)

Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: FT0019A (referred to as the EUT in this report) is the Radio Detection and Ranging Device for Vehicle.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 4 of 21 Issued date : March 13, 2012 Revised date : March 15, 2012 FCC ID : BABFT0019A

SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C: 2012, final revised on February 1, 2012

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators

Section 15.253 Operation within the bands 46.7-46.9GHz and 76.0-77.0GHz.

3.2 Procedures and results

Item	Test Procedure	Specification	Worst margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.4:2003 7. AC power line Conducted Emission measurements IC: RSS-Gen 7.2.4	FCC: Section 15.207 IC: RSS-Gen 7.2.4	·N/A	N/A	*1)
26dB Bandwidth	FCC: "MILLIMETER WAVE TEST PROCEDURES" IC: -	FCC: Section 15.253(e) IC: RSS-210 A13.1.5		Complied	Radiated
Power Density	FCC: "MILLIMETER WAVE TEST PROCEDURES" IC: -		See data.	Complied	Radiated
Spurious Emissions	FCC: ANSI C63.4:2003, "MILLIMETER WAVE TEST PROCEDURES" IC: RSS-Gen 4.9	FCC: Section 15.253(c), (d) IC: RSS-210 A13.1.2(2), A13.1.4, RSS-Gen 7.2.3	2.2dB 9563.165MHz, AV, Vertical	Complied	Radiated
Frequency Stability	FCC: "MILLIMETER WAVE TEST PROCEDURES" IC: RSS-Gen 4.7, 7.2.4	FCC: Section 15.253(e) IC: RSS-210 A13.1.5	See data.	Complied	Radiated

^{*1)} The test is not applicable since the EUT is not the device that is designed to be connected to the public utility (AC) power line Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.

Millimeter wave measurement was performed accordance with FCC KDB 200443 (MILLIMETER WAVE TEST PROCEDURES).

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

^{*} In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

 Page
 : 5 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Bandwidth	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	N/A	-	Radiated

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room		Radiated emission							
(semi-		(3m*)(<u>+</u> dB))(<u>+</u> dB)	$(0.5\text{m*})(\underline{+}\text{dB})$		
anechoic	9kHz	30MHz	300MHz	1GHz	10GHz	18GHz	26.5GHz		
chamber)	-30MHz	-300MHz	-1GHz	-10GHz	-18GHz	-26.5GHz	-40GHz		
No.1	4.2dB	5.0dB	5.1dB	4.7dB	5.7dB	4.4dB	4.3dB		
No.2	4.1dB	5.2dB	5.1dB	4.8dB	5.6dB	4.3dB	4.2dB		
No.3	4.5dB	5.0dB	5.2dB	4.8dB	5.6dB	4.5dB	4.2dB		
No.4	4.7dB	5.2dB	5.2dB	4.8dB	5.6dB	5.1dB	4.2dB		

^{*3}m/1m/0.5m = Measurement distance

Radiated emission (<u>+</u> dB)					
40GHz-50GHz	3.9dB				
50GHz-75GHz	5.1dB				
75GHz-110GHz	5.4dB				
110GHz-170GHz	5.2dB				
170GHz-260GHz	5.2dB				

Radiated emission test(3m)

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

Power Density

The data listed in this test report has enough margin, more than the site margin.

Head Office EMC Lab.

 $4383\text{-}326 \; Asama\text{-}cho, \, Ise\text{-}shi, \, Mie\text{-}ken \; 516\text{-}0021 \; JAPAN$

 Page
 : 6 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. *NVLAP Lab. code: 200572-0

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone: +81 596 24 8116 Facsimile: +81 596 24 8124

	FCC	IC Registration	Width x Depth x	Size of	Other
	Registration Number	Number	Height (m)	reference ground plane (m) / horizontal conducting plane	rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

^{*} Size of vertical conducting plane (for Conducted Emission test): 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Data of EMI, Test instruments, and Test set up

Refer to APPENDIX.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

 Page
 : 7 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Mode	Test Item			
Operating mode (In motion) *1)	26dB Bandwidth			
	Power Density			
	Spurious Emission			
	Frequency Stability			
End users cannot change the settings of the output pov	wer of the product.			
*1) All test items were performed on "In motion" mode, since the EUT is controlled by vehicle's computer to radiate only when the vehicle is moving.				

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

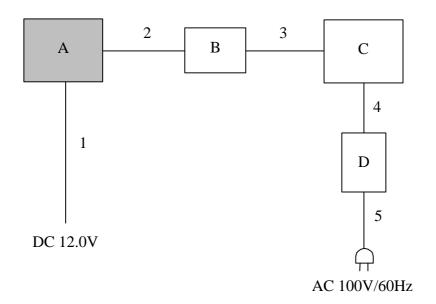
 Page
 : 8 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

4.2 Configuration and peripherals



^{*} Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

Description of EUT

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Radio Detection and Ranging	FT0019A	10102	FUJITSU TEN	EUT
	Device for Vehicle			LIMITED	
В	CANcab	251	-	vector	-
C	Laptop PC	FMVNAL3HCA	R5306361	FUJITSU LIMITED	-
D	AC Adaptor	FMV-AC312	052510895B	FUJITSU LIMITED	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	DC Cable	2.0	Unshielded	Unshielded	-
2	CAN Cable	2.3	Unshielded	Unshielded	-
3	Signal Cable	0.3	Unshielded	Unshielded	-
4	DC Cable	1.8	Unshielded	Unshielded	-
5	AC Cable	1.9	Unshielded	Unshielded	-

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

 Page
 : 9 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

SECTION 5: Radiated Emission (Spurious Emission, Power Density)

Test Procedure [Up to 40GHz]

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m(9kHz-10GHz), 0.5m by 0.5m(10GHz-40GHz), raised 0.8m(9kHz-10GHz), 1.0m(10GHz-40GHz) above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane. The height of the measuring antenna varied between 1 and 4m (frequency 9kHz-30MHz: loop antenna was fixed height at 1.0m) and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength. The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer. The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table. When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency	Below 30MHz	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Loop	Biconical	Logperiodic	Horn

Frequency	9kHz-150kHz	150kHz-30MHz	30MHz-1GHz	1GHz-231GHz	
Instrument used	Test Receiver	Test Receiver	Test Receiver	Spectrum Analy	zer
Detector	QP, AV	QP, AV	QP	PK	AV
IF Bandwidth	BW 200Hz	BW 9kHz	BW 120kHz	RBW: 1MHz	RBW: 1MHz
				VBW: 3MHz	VBW: 10Hz
					*1)
Test Distance	3m	3m	3m	3m (below 10GHz),	
				1m*2) (above 10GHz),	
				0.5m*3) (26.5 - 40GHz)	
				Above 40GHz:	
				For more details	s, refer to next page.

^{*1)} The test was performed with VBW 10Hz since the harmonics of oscillation (9.6GHz VCO) had continuously oscillated, except for carrier frequency.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

^{*2)} Distance Factor: 20 x log (3.0m/1.0m) = 9.5dB *3) Distance Factor: 20 x log (3.0m/0.5m) = 15.6dB

 Page
 : 10 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

[Above 40GHz]

The test was performed based on "MILLIMETER WAVE TEST PROCEDURES".

The EUT was placed on a urethane platform, raised 1.0m above the conducting ground plane.

The measurements were performed on handheld method.

Set spectrum analyzer RBW, VBW, span, etc., to the proper values. Note these values. Enable two traces—one set to "clear write," and the other set to "max hold."

Begin hand-held measurements with the test antenna (horn) at a distance of 1 m from the EUT in a horizontally polarized position. Slowly adjust its position, entirely covering the plane 1 m from the EUT.

Observation of the two active traces on the spectrum analyzer will allow refined horn

positioning at the point(s) of maximum field intensity. Repeat with the horn in a vertically polarized position. If the emission cannot be detected at 1 m, reduce the RBW to increase system sensitivity. Note the value. If the emission still cannot be detected, move the horn closer to the EUT, noting the distance at which a measurement is made.

Note the maximum level indicated on the spectrum analyzer. Adjust this level, if necessary, by the antenna gain, conversion loss of the external mixer and gain of LNA used, at the frequency under investigation. Calculate the field strength of the emission at the measurement distance from the Friis' transmission equation.

[About carrier measurement]

The carrier levels were confirmed at maximum direction of transmission. The maximum direction was searched under carefully since beam-widths are extremely narrow.

The carrier levels were measured in the far field. The distance of the far field was calculated from follow equation.

$$r = \frac{2D^2}{\lambda}$$

where

r is the distance from the radiating element of the EUT to the edge of the far field, in m D is the largest dimension of both the radiating element and the test antenna (horn), in m Lambda is the wavelength of the emission under investigation [300/f (MHz)], in m

Frequency	Lambda	Maxi	Far Field		
		H V Diagona			Boundary
[GHz]	[mm]	[mm]	[mm]	D [m]	r [m]
77.0	3.9	91.4	61.5	0.110	6.3

The test was made on EUT at the normal use position since the installation position was decided based on "Theory of operation".

For the carrier measurement, the measuring antenna was angularly-tilted, since the EUT has angularly-tilted linear polarized antenna.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Measurement range : 9k-231GHz
Test data : APPENDIX
Test result : Pass

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

 Page
 : 11 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

SECTION 6: Frequency Stability

Test Procedure

The external mixer was placed in side of the temperature chamber drain hole.

The power supply set to 100 % nominal setting, raise EUT operating temperature to 50 deg. C.

Record the frequency excursion of the EUT emission mask.

Repeat measurements at each 10 deg. C increment down to -20 deg. C.

Varied EUT power supply between 85% and 115% of nominal and record the frequency excursion of the EUT emission mask when temperature is $20\deg$. C.

Emission mask was measured 26dB bandwidth.

Test data : APPENDIX

Test result : Pass

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

 Page
 : 12 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

APPENDIX 1: Data of EMI test

26dB and 99% Bandwidth

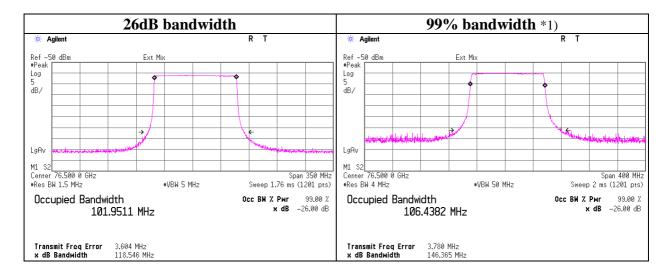
Test place Head Office EMC Lab. No.3 Semi Anechoic Chamber

Report No. 32GE0069-HO-01 Date 02/28/2012

Temperature/ Humidity
Engineer
Hironobu Ohnishi
Mode

23 deg. C / 32% RH
Hironobu Ohnishi
Operating mode

Frequency	26dB	99% Occupied
	Bandwidth	Bandwidth
[GHz]	[MHz]	[MHz]
76.500	118.546	106.438



*1) The measurement was performed with Peak detector, Max Hold since the duty cycle was not 100%.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

 Page
 : 13 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

Power Density

Test place Head Office EMC Lab. No.3 Semi Anechoic Chamber

Report No. 32GE0069-HO-01 Date 02/28/2012

Temperature/ Humidity
Engineer
Hironobu Ohnishi
Mode

23 deg. C / 32% RH
Hironobu Ohnishi
Operating mode

Mode	Frequency	Measurement	Measured	Rx Antenna	System	LNA	Free field
		Distance	Power	Gain	Loss	Gain	Attenuation
	[GHz]	[m]	[dBm]	[dBi]	[dB]	[dB]	[dB]
Operating mode	76.47083	6.5	-67.33	22.32	41.96	0.00	86.37

Mode	Peak EIRP S		Specification Power Den		Limit	Margin
			Distance	Pk	Pk	Pk
	[dBm]	[mW]	[m]	[uW/cm2]	[uW/cm2]	[dB]
Operating mode	38.68	7376.6	3.0	6.522	6000	29.64

Mode	Duty	Average	EIRP	Specification	Power Density	Limit	Margin
	Factor *	(Peak with Duty Factor)		Distance	Av	Av	Av
	[dB]	[dBm]	[mW]	[m]	[uW/cm2]	[uW/cm2]	[dB]
Operating mode	-3.01	35.67	3688.3	3.0	3.261	60	12.65

^{* 10}log(0.5): Since duty is 50%, Refer to exhibit "Theory of operation"

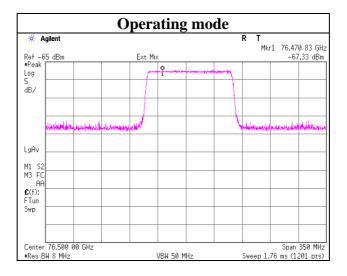
Calculating formula:

Free Field Attenuation = 10 * log((4 * pi * Measurement Distance / lambda) ^ 2)

Peak EIRP = Measured Power - Rx Antenna Gain + System Loss - LNA Gain + Free Field Attenuation

 $Average\ EIRP = Peak\ EIRP + Duty\ Factor$

Power Density = EIRP / (4 * pi * Specification Distance ^ 2)



^{*} The peak power density complies with both peak and average limits.

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

^{*} As for the limit, 60uW/cm² of §15.253 (b) (2) was applied to the EUT based on "Theory of operation".

 Page
 : 14 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

Spurious Emission

Report No. 32GE0069-HO-01 Test place Head Office EMC Lab.

 Semi Anechoic Chamber
 No.4
 No.3

 Date
 02/25/2012
 02/28/2012

Temperature/ Humidity

22 deg. C / 30% RH

Engineer

Hironobu Ohnishi

(9kHz-18GHz)

02/25/2012

02/25/2012

02/25/2012

02/25/2012

03/25/2012

03/25/2012

03/25/2012

03/25/2012

03/25/2012

03/25/2012

03/25/2012

03/25/2012

03/25/2012

03/25/2012

03/25/2012

03/25/2012

03/25/2012

Mode Operating mode

Polarity	Frequency	Detector	Reading	Ant.Fac.	Loss	Gain	Result	Limit	Margin	Remark
	[MHz]		[dBuV]	[dB/m]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	
Hori	89.599	QP	26.4	8.2	7.9	32.2	10.3	43.5	33.2	
Hori	447.998	QP	29.9	18.3	10.8	32.1	26.9	46.0	19.1	
Hori	9563.165	PK	47.0	38.3	4.8	33.2	56.9	73.9	17.0	
Hori	19125.340	PK	52.0	37.9	-2.5	32.2	55.2	73.9	18.7	
Hori	28688.220	PK	40.8	40.0	-10.1	24.8	45.9	73.9	28.0	
Hori	38251.330	PK	43.7	42.0	-9.0	24.0	52.7	73.9	21.2	
Hori	9563.165	AV	41.1	38.3	4.8	33.2	51.0	53.9	2.9	VBW=10Hz
Hori	19125.340	AV	48.0	37.9	-2.5	32.2	51.2	53.9	2.7	VBW=10Hz
Hori	28688.220	AV	34.5	40.0	-10.1	24.8	39.6	53.9	14.3	VBW=10Hz
Hori	38251.330	AV	33.3	42.0	-9.0	24.0	42.3	53.9	11.6	VBW=10Hz
Vert	89.599	QP	32.5	8.2	7.9	32.2	16.4	43.5	27.1	
Vert	447.998	QP	27.0	18.3	10.8	32.1	24.0	46.0	22.0	
Vert	9563.165	PK	47.6	38.3	4.8	33.2	57.5	73.9	16.4	
Vert	19125.340	PK	49.2	37.9	-2.5	32.2	52.4	73.9	21.5	
Vert	28688.220	PK	42.7	40.0	-10.1	24.8	47.8	73.9	26.1	
Vert	38251.330	PK	44.0	42.0	-9.0	24.0	53.0	73.9	20.9	
Vert	9563.165	AV	41.8	38.3	4.8	33.2	51.7	53.9	2.2	VBW=10Hz
Vert	19125.340	AV	46.0	37.9	-2.5	32.2	49.2	53.9	4.7	VBW=10Hz
Vert	28688.220	AV	37.2	40.0	-10.1	24.8	42.3	53.9	11.6	VBW=10Hz
Vert	38251.330	AV	34.6	42.0	-9.0	24.0	43.6	53.9	10.3	VBW=10Hz

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter-Distance factor(above 10GHz)) - Gain(Amplifier) *Other frequency noises omitted in this report were not seen or had enough margin (more than 20dB).

 $\begin{array}{lll} \mbox{Distance factor:} & 10\mbox{GHz-26.5GHz} & 20\mbox{log}(3.0\mbox{m}/1.0\mbox{m}) = 9.5\mbox{dB} \\ 26.5\mbox{GHz-40\mbox{GHz}} & 20\mbox{log}(3.0\mbox{m}/0.5\mbox{m}) = 15.6\mbox{dB} \end{array}$

The average measurement was performed with VBW 10Hz since the harmonics of oscillation (9.6GHz VCO) had continuously oscillated.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

 Page
 : 15 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

Spurious Emission (above 40GHz)

Test place Head Office EMC Lab. No.4 Semi Anechoic Chamber

Report No. 32GE0069-HO-01

Date 02/28/2012 03/01/2012

Temperature/ Humidity 23 deg. C / 32% RH 22 deg. C / 30% RH Engineer Hironobu Ohnishi Hironobu Ohnishi

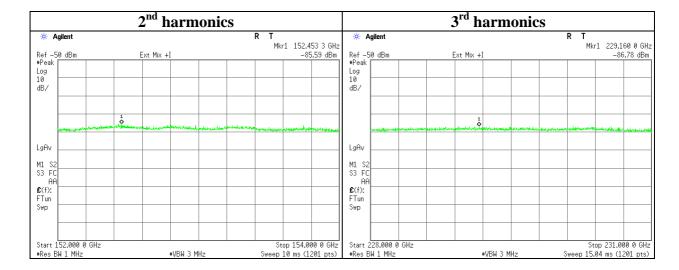
(40-50GHz) (50-231GHz)

Mode Operating mode

* The peak density is less than the average limit.

There is no spurious emission from 40GHz to 231GHz except for operating band.

The following shows the measurement results of the harmonics.



Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

 Page
 : 16 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

Frequency Stability

Test place Head Office EMC Lab. No.6 Shielded room

Report No. 32GE0069-HO-01 Date 02/23/2012

Temperature/ Humidity
Engineer
Hironobu Ohnishi
Mode

23 deg. C / 35% RH
Hironobu Ohnishi
Operating mode

Test Condition		Center	Frequency	26dB	Lower	Upper
Temperature	Power Supply	Frequency	Error	Bandwitdh	Frequency	Frequency
[deg. C]	[V]	[GHz]	[MHz]	[MHz]	[GHz]	[GHz]
50	12.0	76.500	-16.854	123.292	76.422	76.545
40	12.0	76.500	-8.748	121.705	76.430	76.552
30	12.0	76.500	1.822	121.377	76.441	76.563
20	12.0	76.500	10.363	124.475	76.448	76.573
10	12.0	76.500	21.159	120.493	76.461	76.581
0	12.0	76.500	30.276	121.061	76.470	76.591
-10	12.0	76.500	40.715	123.459	76.479	76.602
-20	12.0	76.500	51.225	120.731	76.491	76.612
20	10.2	76.500	10.511	122.037	76.449	76.572
20	13.8	76.500	10.717	121.152	76.450	76.571
20	9.0	76.500	9.760	123.439	76.448	76.571
20	16.0	76.500	10.249	121.814	76.449	76.571

Calculating formula:

 $Lower\ Frequency = Center\ Frequency + Frequency\ Error - 26dB\ Bandwidth\ /\ 2$ $Upper\ Frequency = Center\ Frequency + Frequency\ Error + 26dB\ Bandwidth\ /\ 2$

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 17 of 21 : March 13, 2012 : March 15, 2012 Issued date Revised date FCC ID : BABFT0019A

APPENDIX 2: Test instruments

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MOS-14	Thermo-Hygrometer	Custom	CTH-201	-	RE	2012/02/06 * 12
MCH-04	Temperature and Humidity Chamber	Tabai Espec	PL-2KP	14015723	RE	2011/08/22 * 12
MHA-11	Horn Antenna	WiseWave	ARH1023-02	10766-01	RE	2011/10/31 * 12
MPA-18	Pre Amplifier	AmTechs Corporation	LNA-7511025	9601	RE	2011/08/27 * 12
MMX-01	Preselected Millimeter Mixer	Agilent	11974V-E01	3001A00412	RE	2011/06/13 * 12
MCC-66	Microwave Cable 1G- 40GHz	Suhner	SUCOFLEX102	28636/2	RE	2011/04/22 * 12
MCC-67	Microwave Cable 1G- 40GHz	Suhner	SUCOFLEX102	28635/2	RE	2011/04/22 * 12
MSA-04	Spectrum Analyzer	Agilent	E4448A	US44300523	RE	2011/04/08 * 12
MAEC-04	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-10005	RE	2011/03/01 * 12
MOS-15	Thermo-Hygrometer	Custom	CTH-180	-	RE	2012/02/06 * 12
MJM-07	Measure	PROMART	SEN1955	-	RE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE	-
MSA-03	Spectrum Analyzer	Agilent	E4448A	MY44020357	RE	2011/11/23 * 12
MTR-07	Test Receiver	Rohde & Schwarz	ESCI	100635	RE	2011/10/19 * 12
MLPA-01	Loop Antenna	Rohde & Schwarz	HFH2-Z2	100017	RE	2011/10/19 * 12
MCC-113	Coaxial cable	Fujikura/Suhner/TSJ	5D-2W(10m)/ SFM141(5m)/ 421-010(1m)/ sucoform141-PE(1m)/ RFM-E121(Switcher)	-/04178	RE	2011/07/04 * 12
MCC-31	Coaxial cable	UL Japan	-	-	RE	2011/07/28 * 12
MPA-14	Pre Amplifier	SONOMA INSTRUMENT	310	260833	RE	2011/03/04 * 12
MAT-09	Attenuator(6dB)	Weinschel Corp	2	BK7973	RE	2011/11/02 * 12
MBA-05	Biconical Antenna	Schwarzbeck	BBA9106	1302	RE	2011/11/16 * 12
MLA-08	Logperiodic Antenna	Schwarzbeck	UKLP9140-A	N/A	RE	2011/11/16 * 12
MCC-50	Coaxial Cable	UL Japan	-	-	RE	2011/03/25 * 12
MHA-21	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	9120D-557	RE	2011/08/11 * 12
MCC-133	Microwave Cable	HUBER+SUHNER	SUCOFLEX104	336164/4(1m) / 340640(5m)	RE	2011/09/07 * 12
MPA-12	MicroWave System Amplifier	Agilent	83017A	MY39500780	RE	2011/03/10 * 12
MAEC-03	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-10005	RE	2011/02/22 * 12
MOS-13	Thermo-Hygrometer	Custom	CTH-180	-	RE	2012/02/06 * 12
MJM-06	Measure	PROMART	SEN1955	-	RE	-
MHA-16	Horn Antenna 15-40GHz	Schwarzbeck	BBHA9170	BBHA9170306	RE	2011/05/23 * 12
MPA-11	MicroWave System Amplifier	Agilent	83017A	MY39500779	RE	2011/03/10 * 12
MCC-140	Microwave Cable	Junkosha	J12J101596-00	JAN-31-12-001	RE	2012/02/24 * 12

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

 Page
 : 18 of 21

 Issued date
 : March 13, 2012

 Revised date
 : March 15, 2012

 FCC ID
 : BABFT0019A

EMI test equipment (2/2)

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MPA-03	Microwave System Power Amplifier	Agilent	83050A	3950M00205	RE	2011/06/15 * 12
MHA-07	Horn Antenna	Custom	HO22R	10766-01	RE	2011/10/31 * 12
MMX-02	Harmonic Mixer	Agilent	11970W	2521 A01909	RE	2011/06/14 * 12
MHA-09	Horn Antenna	WiseWave	ARH1523-02	10766-01	RE	2011/10/31 * 12
MPA-08	Pre Amplifier	WiseWave	ALN-61226028-51	11576-01-071	RE	2011/08/27 * 12
MHA-24	Horn Antenna	Custom Microwave Inc.	HO6R	-	RE	2011/09/19 * 12
MMX-03	Harmonic Mixer	OML Inc.	M06HWD	D100709-1	RE	2011/09/30 * 12
MHA-27	Horn Antenna	Custom Microwave Inc.	HO4R	-	RE	2011/09/19 * 12
MMX-04	Harmonic Mixer	OML Inc.	M04HWD	Y100709-1	RE	2011/09/30 * 12
MDPLX-01	Diplexer	OML Inc.	DPL26	-	RE	2011/09/19 * 12
MCC-135	Microwave Cable	HUBER+SUHNER	SUCOFLEX102	37511/2	RE	2011/08/31 * 12

The expiration date of the calibration is the end of the expired month.

[Below 40GHz]

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

[Above 40GHz]

Acceptance criteria for untraceable equipment was formulated according to ISO/IEC 17025 5.6.2.2.2, and the regular inspection was performed based on it annually.

For 40-110GHz, power sensor is calibrated by manufacturer, and the measured calibration data is used as inhouse reference. The calibration data by manufacturer is checked for acceptance by a calorie meter except for some frequency bands.

For above 110GHz, output level of millimeter wave source module is used as the reference, and inspection by the calorie meter is performed.

Electric power is checked with the calorie meter by measuring resistance and voltage of reference resistor.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

RE: Radiated Emission

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN